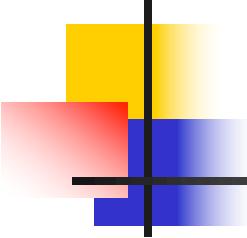


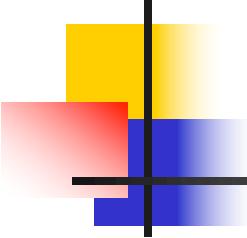
Lab N° 3

Design for Testability



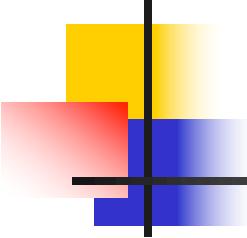
Objectives

- Realise the full synthesis flow
 - Start from an existing design
 - Use the synthesis tool « Design Compiler » from eSynopsys
 - Use the test tool test « Tetramax » from Synopsys



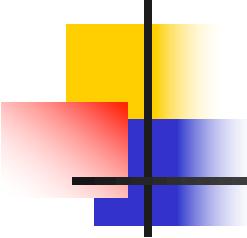
Design

- A 8-bit filter
 - Composed of an adder and two 8-bit register
 - Source file in the directory
 - ... /VHDL



Synthesis

- Tool **dc_shell-xg-t** (Design Compiler from Synopsys)
 - Necessary scripts are available in the directory
 - ... /Synth
 - .synopsys_dc.setup
 - synthesize_dc_shell.scr

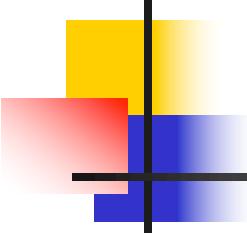


Test

- Use Tetramax to generate test patterns
 - Comment and analyse the obtained results in terms of testable and non-testable faults
 - Comparer le TC avec et sans SCAN

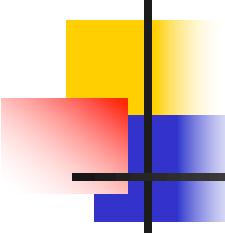


- Modify the circuit by adding physically the scan path
 - Use the tool **dc_shell-xg-t**



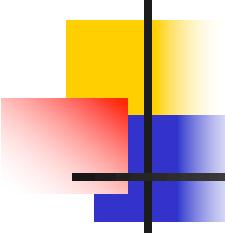
Commands

- Read the file
 - `read_verilog <ckt.v>`
- Specify the top module
 - `current_design <top module name>`



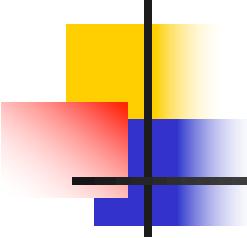
Commands

- Specify the type of scan chain
 - FF type
 - `set test_default_scan_style multiplexed_flip_flop`
 - Number of scan chain
 - `set_scan_configuration -chain_count <n>`



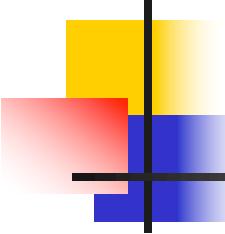
Commands

- Add test input/output:
 - Test_mode
 - Test_si
 - Test_so
 - Test_se
- Create_port <name> -direction <in | out | inout>



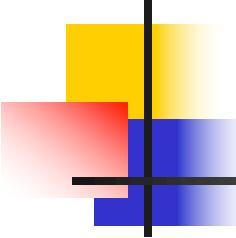
Commands

- Specify the signals that are controlling the scan chain:
 - Clock
 - Set|reset
 - Test_mode
 - Test_si
 - Test_so
 - Test_se



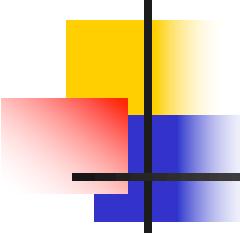
Commands

- `set_dft_signal -view exist -type ScanClock -timing {45 55} -port < clk >`
- `set_dft_signal -view exist -type Reset -active_state 0 –port < reset >`
- `set_dft_signal -view spec -type Constant -active_state 1 -port < test mode >`
- `set_dft_signal -view spec -type ScanDataIn -port < test si >`
- `set_dft_signal -view spec -type ScanDataOut -port < test so >`
- `set_dft_signal -view spec -type ScanEnable –port < test se >`



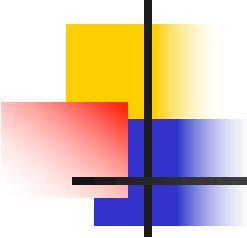
Commands

- Create the test protocol
 - `create_test_protocol`
- Add the scan chain
 - `dft_drc`
 - `preview_dft`
 - `insert_dft`
- Visualize the scan chain
 - `report_scan_path`



Commands

- Save the test protocol
 - `write_test_protocol -o < file.spf >`
- Save the modify circuit
 - `write -format verilog -hierarchy –output < ckt.v >`



Test

- Use Tetramax to check if the test protocol and the circuit with the scan chain are correct
- Generate test vectors and save them